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Application/Control No.	Applicant(s)/Patent under Reexamination
10/764,374	SATOH ET AL.
Examiner	Art Unit
Chen-Wen Jiang	3744

	SEAR	CHED	
Class	Subclass	Date	Examiner
62	238.7		
237	2B		
203	11	3/28/2006	C1
Search	Updated	9/26/2006	C1

INT	ERFERENC	CE SEARCH	ED
Class	Subclass	Date	Examiner
62	238.7	9/26/2006	cı

SEARCH N (INCLUDING SEARC)
	DATE	EXMR
EAST Searched Inventor Searched	3/28/2006	CJ
Interference Search Printed	9/26/2006	CJ
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